PIN Photodiodes

PNZ323B (PN323B)

Silicon planar type

For optical control systems

■ Features

• Fast response which is well suited to high speed modulated light detection: $t_r, t_f = 50 \text{ ns (typ.)}$
• High sensitivity, high reliability
• Peak emission wavelength matched with infrared light emitting diodes: $\lambda_p = 970 \text{ nm (typ.)}$
• Wide detection area, wide half-power angle: $\theta = 70^\circ$ (typ.)
• Adoption of visible light cutoff resin

■ Absolute Maximum Ratings $T_a = 25^\circ \text{C}$

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Symbol</th>
<th>Rating</th>
<th>Unit</th>
</tr>
</thead>
<tbody>
<tr>
<td>Reverse voltage</td>
<td>$V_R$</td>
<td>30</td>
<td>V</td>
</tr>
<tr>
<td>Power dissipation</td>
<td>$P_D$</td>
<td>100</td>
<td>mW</td>
</tr>
<tr>
<td>Operating ambient temperature</td>
<td>$T_{opp}$</td>
<td>$-30$ to $+85$</td>
<td>$^\circ \text{C}$</td>
</tr>
<tr>
<td>Storage temperature</td>
<td>$T_{stg}$</td>
<td>$-40$ to $+100$</td>
<td>$^\circ \text{C}$</td>
</tr>
</tbody>
</table>

■ Electrical-Optical Characteristics $T_a = 25^\circ \text{C} \pm 3^\circ \text{C}$

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Symbol</th>
<th>Conditions</th>
<th>Min</th>
<th>Typ</th>
<th>Max</th>
<th>Unit</th>
</tr>
</thead>
<tbody>
<tr>
<td>Dark current</td>
<td>$I_D$</td>
<td>$V_R = 10 \text{ V}$</td>
<td>5</td>
<td>50</td>
<td>nA</td>
<td></td>
</tr>
<tr>
<td>Photocurrent *1</td>
<td>$I_L$</td>
<td>$V_R = 10 \text{ V}$, $L = 1000 \text{ lx}$</td>
<td>31</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Sensitivity to infrared radiation *2</td>
<td>$S_{IR}$</td>
<td>$V_R = 5 \text{ V}$, $H = 0.1 \text{ mW/cm}^2$</td>
<td>3.2</td>
<td>4.0</td>
<td>$\mu\text{A}$</td>
<td></td>
</tr>
<tr>
<td>Peak emission wavelength</td>
<td>$\lambda_p$</td>
<td>$V_R = 10 \text{ V}$</td>
<td>970</td>
<td></td>
<td></td>
<td>nm</td>
</tr>
<tr>
<td>Rise time *3</td>
<td>$t_r$</td>
<td>$V_R = 10 \text{ V}$, $R_L = 1 \text{ k}\Omega$</td>
<td>50</td>
<td></td>
<td></td>
<td>$\text{ns}$</td>
</tr>
<tr>
<td>Fall time *3</td>
<td>$t_f$</td>
<td>$V_R = 10 \text{ V}$, $R_L = 100 \text{ k}\Omega$</td>
<td>50</td>
<td></td>
<td></td>
<td>$\text{ns}$</td>
</tr>
<tr>
<td>Rise time *3</td>
<td>$t_r$</td>
<td>$V_R = 10 \text{ V}$, $R_L = 100 \text{ k}\Omega$</td>
<td>5</td>
<td></td>
<td></td>
<td>$\mu\text{s}$</td>
</tr>
<tr>
<td>Fall time *3</td>
<td>$t_f$</td>
<td>$V_R = 10 \text{ V}$, $R_L = 100 \text{ k}\Omega$</td>
<td>5</td>
<td></td>
<td></td>
<td>$\mu\text{s}$</td>
</tr>
<tr>
<td>Terminal capacitance</td>
<td>$C_t$</td>
<td>$V_R = 0 \text{ V}$, $f = 1 \text{ MHz}$</td>
<td>70</td>
<td></td>
<td></td>
<td>$\text{pF}$</td>
</tr>
<tr>
<td>Half-power angle</td>
<td>$\theta$</td>
<td>The angle from which photocurrent becomes 50%</td>
<td>70</td>
<td></td>
<td></td>
<td>$^\circ$</td>
</tr>
</tbody>
</table>

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7031 measuring methods for diodes.
2. Spectral sensitivity characteristics: Sensitivity for wave length over 400 nm maximum sensitivity ratio is 100%.
3. This device is designed be disregarded radiation.
4. *1: Source: Tungsten (color temperature 2856 K)
   *2: Source: Infrared radiation ($\lambda = 940 \text{ nm}$)
   *3: Switching time measurement circuit

Note) The part number in the parenthesis shows conventional part number.
**PNZ323B**

---

**Power dissipation** $P_D$ (mW) vs. Ambient temperature $T_a$ (°C)

**Photocurrent** $I_L$ (µA) vs. Illuminance $L$ (lx)

**Dark current** $I_D$ (nA) vs. Ambient temperature $T_a$ (°C)

**Relative photocurrent** $\Delta I_L$ (%) vs. Ambient temperature $T_a$ (°C)

**Spectral sensitivity characteristics**

**Directivity characteristics**

**Terminal capacitance** $C_t$ (pF) vs. Reverse voltage $V_R$ (V)

**Rise time** $t_r$, **Fall time** $t_f$ vs. Load resistance $R_L$ (kΩ)

**Dark current** $I_D$ (nA) vs. Reverse voltage $V_R$ (V)
Request for your special attention and precautions in using the technical information and semiconductors described in this material

(1) An export permit needs to be obtained from the competent authorities of the Japanese Government if any of the products or technical information described in this material and controlled under the "Foreign Exchange and Foreign Trade Law" is to be exported or taken out of Japan.

(2) The technical information described in this material is limited to showing representative characteristics and applied circuits examples of the products. It neither warrants non-infringement of intellectual property right or any other rights owned by our company or a third party, nor grants any license.

(3) We are not liable for the infringement of rights owned by a third party arising out of the use of the technical information as described in this material.

(4) The products described in this material are intended to be used for standard applications or general electronic equipment (such as office equipment, communications equipment, measuring instruments and household appliances).
Consult our sales staff in advance for information on the following applications:
• Special applications (such as for airplanes, aerospace, automobiles, traffic control equipment, combustion equipment, life support systems and safety devices) in which exceptional quality and reliability are required, or if the failure or malfunction of the products may directly jeopardize life or harm the human body.
• Any applications other than the standard applications intended.

(5) The products and product specifications described in this material are subject to change without notice for modification and/or improvement. At the final stage of your design, purchasing, or use of the products, therefore, ask for the most up-to-date Product Standards in advance to make sure that the latest specifications satisfy your requirements.

(6) When designing your equipment, comply with the guaranteed values, in particular those of maximum rating, the range of operating power supply voltage, and heat radiation characteristics. Otherwise, we will not be liable for any defect which may arise later in your equipment.
Even when the products are used within the guaranteed values, take into the consideration of incidence of break down and failure mode, possible to occur to semiconductor products. Measures on the systems such as redundant design, arresting the spread of fire or preventing glitch are recommended in order to prevent physical injury, fire, social damages, for example, by using the products.

(7) When using products for which damp-proof packing is required, observe the conditions (including shelf life and amount of time let standing of unsealed items) agreed upon when specification sheets are individually exchanged.

(8) This material may be not reprinted or reproduced whether wholly or partially, without the prior written permission of Matsushita Electric Industrial Co., Ltd.